. 41			285A R			
	F INFORMATION DISCLO Under 37 CFR 1.97(b) or 1.97		Docket No. TIL0004			
In Re Application Of:	In Re Application Of: Hans-Ulrich Krotil et al.					
Serial No. 09/869,789	TRADE					
Title: METHOD AND I	DEVICE FOR SIMULTANEOUSI RIAL PROPERTIES OF A SAMPL		1			
_			800 T ENT			
	Commiss P.O	ddress to: sioner for Patents D. Box 1450 a, VA 22313-1450	HESION, FRICTION, AND RECEIVED			
	37 C	FR 1.97(b)	•			
of a national ap three months of application; befo	 The Information Disclosure Statement submitted herewith is being filed within three months of the filing of a national application other than a continued prosecution application under 37 CFR 1.53(d); within three months of the date of entry of the national stage as set forth in 37 CFR 1.491 in an international application; before the mailing of a first Office Action on the merits, or before the mailing of a first Office Action after the filing of a request for continued examination under 37 CFR 1.114. 					
	37 C	FR 1.97(c)				
CFR 1.97(b), pi Final Action un	2. The Information Disclosure Statement submitted herewith is being filed after the period specified in 37 CFR 1.97(b), provided that the Information Disclosure Statement is filed before the mailing date of a Final Action under 37 CFR 1.113, a Notice of Allowance under 37 CFR 1.311, or an Action that otherwise closes prosecution in the application, and is accompanied by one of:					
☐ the stater	ment specified in 37 CFR 1.97(e);					
	OR		•			
	et forth in 37 CFR 1.17(p).					
1/07/2003 SDIRETAI 00000136 FC:1866	09869789 180.00 gp					

Ŧ

TRANSMITTAL OI	Docket No. TIL0004					
In Re Application: Hans-Ulrich Krotil et al.						
Serial No.	Filing Date	TRADE ME Examiner	Group Art Unit			
09/869,789	July 23, 2002	Thomas Noland	2856			
METHOD AND D	EVICE FOR SIMULTANEOU	SLY DETERMINING THE ADI	HESION, FRICTION,			
OTHER MATER	OTHER MATERIAL PROPERTIES OF A SAMPLE SURFACE					
as described belo □ Charge th ☑ Credit an ☑ Charge a	(Only complete if Applicant of \$180.00 is at ereby authorized to charge and ow. ne amount of y overpayment. ny additional fee required.		02-0385			
I certify that this docum	Fransmission by Facsimile* ent and authorization to charge depos mile transmitted to the United State	I certify that this document	ag by First Class Mail t and fee is being deposited with the U.S. Postal Service			
Patent and Trademark ((Date)	Office (F:	11 11 1	er 37 C.F.R. 1.8 and is sioner for Patents, P.O. Box 13-1450.			
(Date)	V		5			
	Signature	Signature of Person John F. Hoffman	n Mailing Correspondence			
Typed or Printed N	Typed or Printed Name of Person Signing Certificate Typed or Printed Name of Person Mailing Certificate					
*This certificate may only be used if paying by deposit account.						
John F. Hoffman, Regis. No. 26,280						
BAKER & DANIELS						
111 East Wayne Street, Suite 800 F rt Wayne, IN 46802						
TX: (260) 424-8000 FAX: (260) 460-17009						
сс:						

PTO/SB/08a (08-03)

Approved for use through 07/31/2006. OMB 0651-0031 Complete if Known

MOV 0 6 2003 U.S. Patent and Trademark Office; U.S. DEPARTMENT OF COMMERCE Under the Paperwork Reduction Act of respond to a collection of information unless it contains a valid OMB control number.

Substitute for form 1449A/PTO

INFORMATION DISCLOSURE STATEMENT BY APPLICANT Application Number 09/869,789 Filing Date July 23, 2002 First Named Inventor Hans-Ulrich Krotil et al. Art Unit 2856 **Examiner Name** Noland, Thomas

(Use as many sheets as necessary)

Attorney Docket Number TIL0004 Sheet

E TRADEWAY

Examiner	Cite	Degument Number	U. S. PATENT I	Name of Patentee or	Pages, Columns, Lines, Where
Initials*	No.1	Document Number Number-Kind Code ^{2 (I known)}	MM-DD-YYYY	Applicant of Cited Document	Relevant Passages or Relevant Figures Appear
		^{US-} 5,444,244	08/22/1995	Kirk et al.	
		^{US-} 5,503,010	04/02/1996	Yamanaka	7 0
		^{US-} 5,519,212	05/21/1996	Elings et al.	0, 7
		^{US-} 5,763,768	06/09/1998	Henderson et al.	100 mg
		^{US-} 5,804,708	09/08/1998	Yamanaka et al.	90 1
		US-			3
		US-			
		US-			ROOM
		US-			Or
		US-			
	-	US-			
	· · · · · · · · · · · · · · · · · · ·	US-			
······································		US-			
		US-			
***************************************		US-			

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	Foreign Patent Document Country Code ³ Number ⁴ 'Kind Code ⁵ (<i>if known</i>)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T6
		EP 0 896 201 A1	02-10-1999	Muramatsu et al.		
***************************************		WO 00/40946	07-13-2000	Stifter et al.		

Examiner	Date	
Signature	Considered	

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. 1 Applicant's unique citation designation number (optional). 2 See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. 3 Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). 4 For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the senal number of the patent document. 5 Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. 6 Applicant is to place a check mark here if English language Translation is attached.

This collection of information is required by 37 CFR 1.97 and 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 2 hours to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, P.O. Box 1450, Alexandria, VA 22313-1450, DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

			Docket Number (Optional)	Application Number
•		IPE	T1L0004	09/869,789
· INF		ATION DISCLOSURE CION TION (Use several sheets if necessary)	Applicant(s) Hans-Ulrich Krotil et al.	
	,	NOV 0 6 2003	Filing Date	Group Art Unit
<u> </u>		\	July 23, 2002	2856
*EXAMINER INITIAL		OTHER DOCUMENT (Including States, Title	le, Date, Pertinent Pages, Etc.)	
		T. Goddenhenrich et al., "A lateral modulation tech atomic force microscope", Rev. Sci. Instrum. 65 (9)	nique for simultaneous friction and Sentember 1994, np. 2870-2873	topography measurements with the
		atomic force fineroscope, Kev. Sci. Histi um. 03 (2)	, ocpiember 1994, pp. 2010-2013.	
		S. Watanabe et al., "Two-directional dynamic mode Technol. B 12(3), May/June 1994, pp. 1577-1580.	e force microscopy: Detection of dir	ectional force gradient", J. Vac. Sci.
		,		
		Kazushi Yamanaka et al., ''Ultrasonic force microse (2), 10 January 1994, pp. 178-180.	copy for nanometer resolution subsu	rface imaging", Appl. Phys. Lett. 64
		(2), 10 January 1994, pp. 178-180.		
				TC A
	_		·	RECEIVED NOV 14 2003 TC 2800 MAIL ROOM
				8 一道
				35、 点
				产量口
				ROC
				3

•				
•				
•				
EXAMINER			DATE CONCIDEDED	
eariminek			DATE CONSIDERED	
'EXAMINER: I	nitial if	citation considered, whether or not citation is in conforma	nce with MPEP Section 609; Draw line t	hrough citation if not in conformance and

not considered. Include copy of this form with next communication to applicant.